Operational Amplifiers, High Slew Rate, Low Voltage, Rail-to-Rail Output

The NCS2003 family of op amps features high slew rate, low voltage operation with rail–to–rail output drive capability. The 1.8 V operation allows high performance operation in low voltage, low power applications. The fast slew rate and wide unity–gain bandwidth (5 MHz at 1.8 V) make these op amps suited for high speed applications. The low input offset voltage (4 mV max) allows the op amp to be used for current shunt monitoring. Additional features include no output phase reversal with overdriven inputs and ultra low input bias current of 1 pA.

The NCS2003 family is the ideal solution for a wide range of applications and products. The single channel NCS2003, dual channel NCS20032, and quad channel NCS20034 are available in a variety of compact and space—saving packages. The NCV prefix denotes that the device is AEC—Q100 Qualified and PPAP Capable.

Features

- Unity Gain Bandwidth: 7 MHz at $V_S = 5 \text{ V}$
- Fast Slew Rate: 8 V/ μ s rising, 12.5 V/ μ s falling at V_S = 5 V
- Rail-to-Rail Output
- No Output Phase Reversal for Over–Driven Input Signals
- Low Offset Voltage: 0.5 mV typical
- Low Input Bias Current: 1 pA typical
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- Current Shunt Monitor
- Signal Conditioning
- Active Filter
- Sensor Buffer

End Products

- Motor Control Drives
- Hard Drives
- Medical Devices
- White Goods and Air Conditioners



ON Semiconductor®

www.onsemi.com



SOT23-5 CASE 483 (NCS/NCV2003)



SOT553, 5 LEAD CASE 463B (NCS2003)



Micro8[™] DM SUFFIX CASE 846A



SOIC-8 CASE 751



TSSOP-8 T SUFFIX CASE 948S



SOIC-14 NB CASE 751A

A = Assembly Location

WL, L = Wafer Lot Y = Year

Y = Year WW, W = Work Week G or ■ = Pb-Free Package

(Note: Microdot may be in either location)

A3M BABBA 2K32 AYW 1 H H H C K32 YWW A • NCS20034G

AWLYWW

H H H H

MARKING DIAGRAMS

ANxYW=

ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 2 of this data sheet.

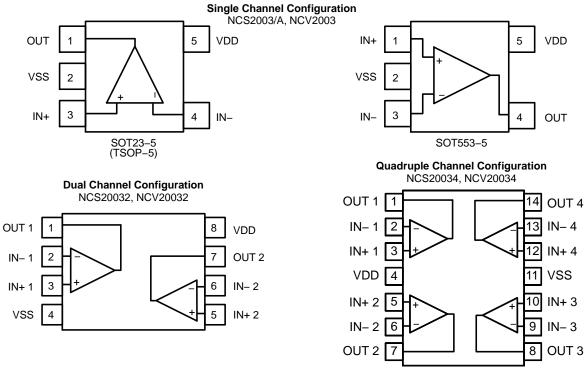


Figure 1. Pin Connections

ORDERING INFORMATION

Device	Configuration	Automotive	Marking	Package	Shipping [†]
NCS2003SN2T1G	Single	No	AN3	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS2003ASN2T1G	7	No	AN4	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS2003XV53T2G		No	А3	SOT553-5 (Pb-Free)	4000 /Tape and Reel
NCV2003SN2T1G*		Yes	AN3	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS20032DMR2G	Dual	No	2K32	Micro8 (Pb–Free)	4000 / Tape and Reel
NCS20032DR2G	7		20032	SOIC-8 (Pb-Free)	2500 / Tape and Reel
NCS20032DTBR2G			K32	TSSOP-8 (Pb-Free)	3000 / Tape and Reel
NCV20032DMR2G*	7	Yes	2K32	Micro8 (Pb–Free)	4000 / Tape and Reel
NCV20032DR2G*	7		20032	SOIC-8 (Pb-Free)	2500 / Tape and Reel
NCV20032DTBR2G*	7		K32	TSSOP-8 (Pb-Free)	3000 / Tape and Reel
NCS20034DR2G	Quad	No	NCS20034G	SOIC-14 (Pb-Free)	2500 / Tape and Reel
NCV20034DR2G*		Yes	NCS20034G	SOIC-14 (Pb-Free)	2500 / Tape and Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

^{*}NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable.

ABSOLUTE MAXIMUM RATINGS

Over operating free-air temperature, unless otherwise stated

Parameter	Parameter			
Supply Voltage (V _{DD} – V _{SS})		V _S	7.0	V
INPUT AND OUTPUT PINS				
Input Voltage (Note 1)		V _{IN}	V _{SS} – 0.3 to 7.0	V
Input Current		I _{IN}	10	mA
Output Short Current (Note 2)		Io	100	mA
TEMPERATURE				
Storage Temperature		T _{STG}	-65 to 150	°C
Junction Temperature		TJ	150	°C
ESD RATINGS (Note 3)				
Human Body Model	NCx2003, A NCx20032 NCx20034	НВМ	3000 2000 3000	V
Machine Model	NCx2003, A NCx20032 NCx20034	MM	200 100 150	V
Charged Device Model	NCx2003, A NCx2003x	CDM	1000 2000	V
OTHER PARAMETERS				•
Moisture Sensitivity Level (Note 5)		MSL	Level 1	
Latch-up Current (Note 4)		I _{LU}	100	mA

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- Neither input should exceed the range of V_{SS} 300 mV to 7.0 V. This device contains internal protection diodes between the input pins and V_{DD}. When V_{IN} exceeds V_{DD}, the input current should be limited to the specified value.
- Indefinite duration; however, maximum package power dissipation limits must be observed to ensure that the maximum junction temperature is not exceeded.
- 3. This device series incorporates ESD protection and is tested by the following methods:
 - ESD Human Body Model tested per AEC-Q100-002 and JESD22-A114
 - ESD Machine Model tested per AEC-Q100-003 and JESD22-A115
 - ESD Charged Device Model tested per AEC-Q100-011 and ANSI/ESD S5.3.1-2009
- 4. Latch-up current tested per JEDEC Standard JESD78.
- 5. Moisture Sensitivity Level tested per IPC/JEDEC standard J-STD-020A.

THERMAL INFORMATION

Thermal Metric	Symbol	Package	Single Layer Board (Note 6)	Multi Layer Board (Note 7)	Unit	
	θЈА	SOT23-5/TSOP-5	408	355		
		SOT553-5	428	406		
Junction to Ambient		0	Micro8/MSOP8	235	163	0000
Thermal Resistance		SOIC-8	240	179	°C/W	
		TSSOP-8	300	238		
		SOIC-14	167	123		

- 6. Values based on a 1S standard PCB according to JEDEC51-3 with 1.0 oz copper and a 300 mm² copper area
- 7. Values based on a 1S2P standard PCB according to JEDEC51-7 with 1.0 oz copper and a 100 mm² copper area

RECOMMENDED OPERATING CONDITIONS

Parar	neter	Symbol	Min	Max	Unit
Operating Supply Voltage (V _{DD} – V _{SS})		V _S	1.7	5.5	V
Specified Operating Range	NCS2003, A NCV2003, NCx20032, NCx20034	T _A	-40 -40	+85 +125	°C
Input Common Mode Range		V _{CM}	V _{SS}	V _{DD} -0.6	V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

ELECTRICAL CHARACTERISTICS: V_S = +1.8 V

At T_A = +25°C, R_L = 10 k Ω connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions		Min	Тур	Max	Unit	
INPUT CHARACTERISTICS				•				
Input Offset Voltage	Vos	NCS2003A			0.5	3.0	mV	
		NCx2003, NCx20032, NCx20034			0.5	4.0	mV	
						5.0	mV	
Offset Voltage Drift	ΔV _{OS} /ΔT				2.0		μV/°C	
		NCS2003A (Not	e 8)			6.0	μV/°C	
Input Bias Current	I _{IB}				1		рА	
Input Offset Current	I _{OS}				1		pA	
Channel Separation	XTLK	DC, NCx20032, NC	x20034		100		dB	
Input Resistance	R _{IN}				1		TΩ	
Input Capacitance	C _{IN}				1.2		pF	
Common Mode Rejection	CMRR	$V_{IN} = V_{SS}$ to V_{DD} -	- 0.6 V	70	80		dB	
Ratio		$V_{IN} = V_{SS} + 0.2 \text{ V to V}$	$V_{IN} = V_{SS} + 0.2 \text{ V to } V_{DD} - 0.6 \text{ V}$					
OUTPUT CHARACTERISTIC	S			I		II.		
Open Loop Voltage Gain	A _{VOL}	R _L = 10 kΩ		80	92		dB	
				75				
		$R_L = 2 k\Omega$			92			
				70				
Output Current Capability	I _{SC}	Sourcing		5	8		mA	
(Note 8)		Sinking		10	14			
Output Voltage High	V _{OH}	$R_L = 10 \text{ k}\Omega$		1.75	1.798		V	
		$R_L = 2 k\Omega$		1.7	1.78			
Output Voltage Low	Vol	R _L = 10 kΩ	NCx2003, A		7	50	mV	
			NCx2003x		7	100		
		$R_L = 2 k\Omega$	<u> </u>		20	100		
NOISE PERFORMANCE				II.	l	ı		
Voltage Noise Density	e _N	f = 1 kHz			20		nV/√ Hz	
Current Noise Density	i _N	f = 1 kHz			0.1		pA√ Hz	
DYNAMIC PERORMANCE	1			ı	1	1		
Gain Bandwidth Product	GBWP				5		MHz	
		Rising Edge, R _L = 2 ks	2, A _V = +1		6			
Slew Rate at Unity Gain	SR	Falling Edge, $R_L = 2 k\Omega$, $A_V = +1$			9		V/μs	
Phase Margin	Ψm		$R_L = 10 \text{ k}\Omega, C_L = 5 \text{ pF}$		53		0	
Gain Margin	A _m	$R_L = 10 \text{ k}\Omega, C_L = 5 \text{ pF}$	NCx2003, A		12		dB	
	. 411	<u>-</u> ·			8		1	
			NCx2003x		0			

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{8.} Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +1.8 V

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions			Тур	Max	Unit
DYNAMIC PERORMANCE					•		
Total Harmonics Distortion +	THD+N	$V_O = 1 V_{pp}, R_L = 2 k\Omega, A_V$	_/ = +1, f = 1 kHz		0.005		%
Noise		$V_O = 1 V_{pp}, R_L = 2 k\Omega, A_V$	= +1, f = 10 kHz		0.025		
POWER SUPPLY							
Power Supply Rejection Ratio	PSRR	NCx2003		72	80		dB
				65			
		NCx20032, NCx	20034	80	100		
Quiescent Current	I _{DD}	No load, per channel	NCx2003, A		230	560	μΑ
						1000	
			NCx20032,		275	375	
			NCx20034			575	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

8. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +5.0 V

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS	S		•			•
Input Offset Voltage	Vos	NCS2003A		0.5	3.0	mV
		NCx2003		0.5	4.0	mV
		NCx20032, NCx20034			5.0	mV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$			2.0		μV/°C
		NCS2003A (Note 9)			6.0	μV/°C
Input Bias Current	I _{IB}			1		pA
Input Offset Current	I _{OS}			1		pA
Channel Separation	XTLK	DC, NCx20032, NCx20034		100		dB
Input Resistance	R _{IN}			1		ΤΩ
Input Capacitance	C _{IN}			1.2		pF

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

9. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +5.0 V

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditi	ons	Min	Тур	Max	Unit
INPUT CHARACTERISTICS	•						1
Common Mode Rejection Ratio	CMRR	NCx2003, A	$V_{IN} = V_{SS}$ to $V_{DD} - 0.6$ V	65	90		dB
			$V_{IN} = V_{SS} + 0.2 \text{ V}$ to $V_{DD} - 0.6 \text{ V}$	63			
		NCx20032, NCx20034	$V_{IN} = V_{SS}$ to $V_{DD} - 0.6$ V	70	90		
			$V_{IN} = V_{SS} + 0.2 \text{ V}$ to $V_{DD} - 0.6 \text{ V}$	65			
OUTPUT CHARACTERISTICS							
Open Loop Voltage Gain	A _{VOL}	R _L = 10	kΩ	86	92		dB
				78			
		R _L = 2	kΩ	83	92		
				78			
Output Current Capability	I _{SC}	Sourcing Sinking		40	76		mA
(Note 9)				50	96		
Output Voltage High	V _{OH}	R _L = 10	kΩ	4.95	4.99		V
		$R_L = 2 k\Omega$		4.9	4.97		
Output Voltage Low	Vol	R _L = 10 kΩ	NCx2003, A		8	50	mV
			NCx2003x		8	100	
		R _L = 2	kΩ		24	100	
NOISE PERFORMANCE							
Voltage Noise Density	e _N	f = 1 k	Hz		20		nV/√ Hz
Current Noise Density	i _N	f = 1 k	Hz		0.1		pA√ Hz
DYNAMIC PERORMANCE							
Gain Bandwidth Product	GBWP				7		MHz
Slew Rate at Unity Gain	SR	Rising Edge, R _L =	2 kΩ, AV = +1		8		V/μs
		Falling Edge, R _L =	2 kΩ, AV = +1		12.5		
Phase Margin	Ψm	$R_L = 10 \text{ k}\Omega, C_L = 5 \text{ pF}$	NCx2003, A		64		٥
			NCx2003x		56		
Gain Margin	A _m	$R_L = 10 \text{ k}\Omega$, (C _L = 5 pF		9		dB
Settling Time	t _S	$V_{O} = 1 V_{pp}$, Gain = 1, $C_{L} = 20 pF$	Settling time to 0.1%		0.6		μs
Total Harmonics Distortion +	THD+N	$V_O = 4 V_{pp}$, $R_L = 2 k\Omega$,	A _V = +1, f = 1 kHz		0.002		%
Noise		$V_O = 4 V_{pp}$, $R_L = 2 k\Omega$,	A _V = +1, f = 10 kHz		0.01		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

9. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +5.0 V

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} =$ midsupply, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions		Min	Тур	Max	Unit
POWER SUPPLY							
Power Supply Rejection Ratio	PSRR	NCx2003	3, A	72	80		dB
				65			
		NCx20032, NCx20034		80	100		
Quiescent Current	I _{DD}	No load, per channel NCx2003, A	NCx2003, A		300	660	μΑ
						1000	
			NCx20032,		325	450	
			NCx20034			675	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{9.} Guaranteed by design and/or characterization.

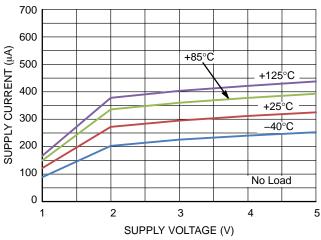


Figure 2. Quiescent Supply Current vs. Supply Voltage

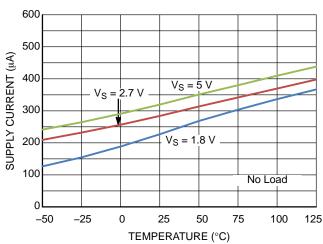


Figure 3. Quiescent Supply Current vs.
Temperature

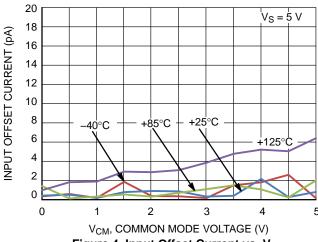


Figure 4. Input Offset Current vs. V_{CM}

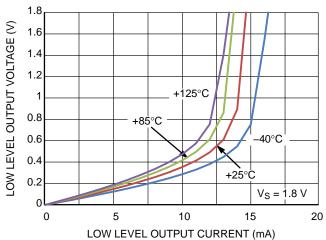


Figure 5. Low Level Output Voltage vs. Output Current @ V_S = 1.8 V

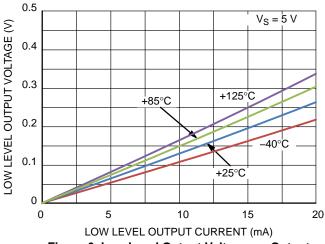


Figure 6. Low Level Output Voltage vs. Output Current @ $V_S = 5 \text{ V}$

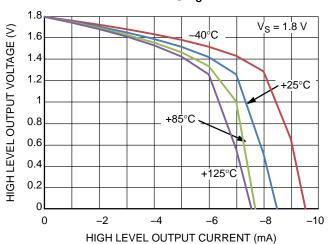


Figure 7. High Level Output Voltage vs. Output Current @ $V_S = 1.8 \text{ V}$

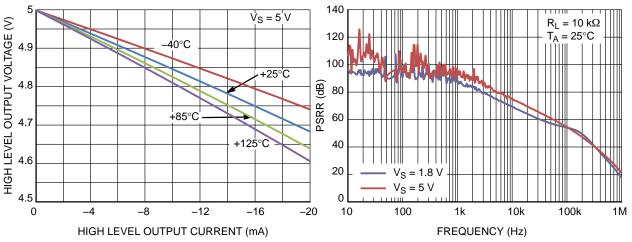


Figure 8. High Level Output Voltage vs. Output Current @ $V_S = 5 V$

Figure 9. PSRR vs. Frequency

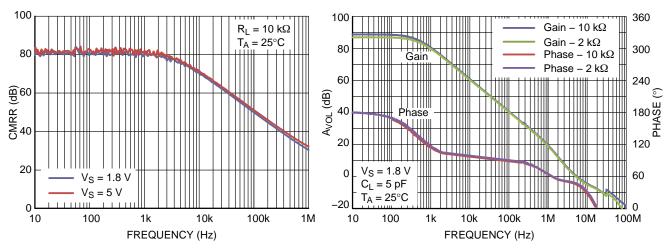


Figure 10. CMRR vs. Frequency

Figure 11. Open Loop Gain and Phase vs. Frequency @ $V_S = 1.8 \text{ V}$

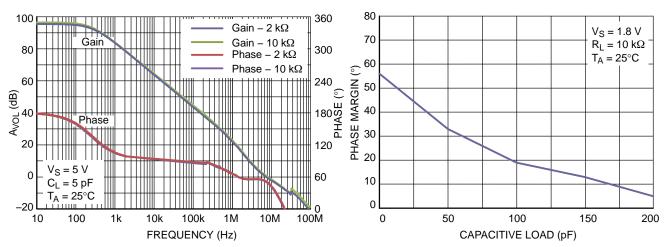


Figure 12. Open Loop Gain and Phase vs. Frequency $@V_S = 5 V$

Figure 13. Phase Margin vs. Capacitive Load

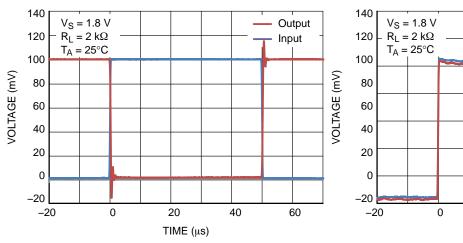
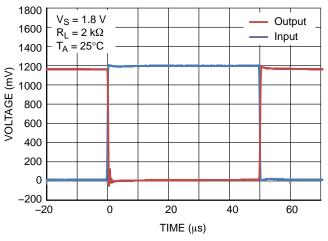


Figure 14. Inverting Small Signal Transient Response

Figure 15. Non-Inverting Small Signal Transient Response



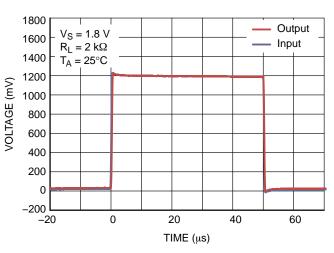
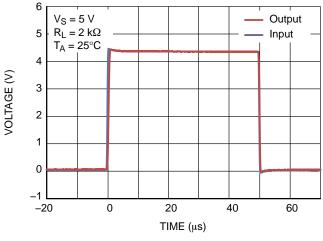


Figure 16. Inverting Large Signal Transient Response

Figure 17. Non-Inverting Large Signal Transient Response



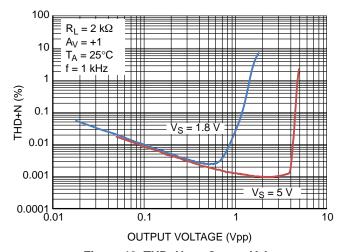
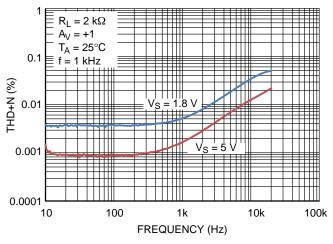


Figure 18. Non-Inverting Large Signal Transient Response

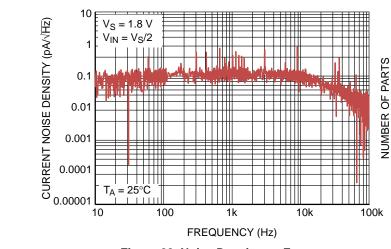
Figure 19. THD+N vs. Output Voltage



140 120 VOLTAGE NOISE (nV/√Hz) = 25°C 100 80 60 40 20 0 10 100 1k 10k 100k FREQUENCY (Hz)

Figure 20. THD+N vs. Frequency

Figure 21. Input Voltage Noise vs. Frequency



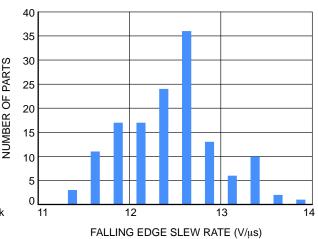
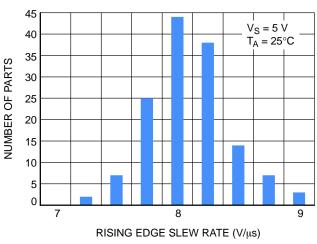


Figure 22. Noise Density vs. Frequency

Figure 23. Falling Edge Slew Rate @ Vs = 5 V



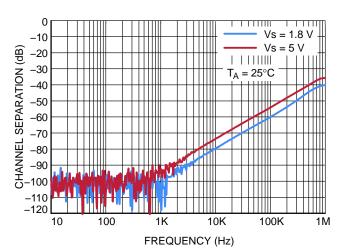
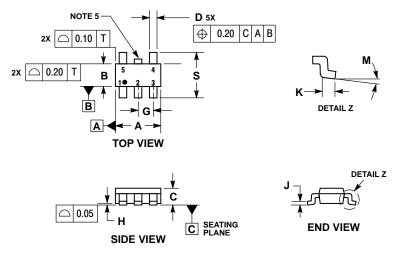


Figure 24. Rising Edge Slew Rate @ Vs = 5 V

Figure 25. Channel Separation

PACKAGE DIMENSIONS

TSOP-5 CASE 483-02 ISSUE K



- NOTES:

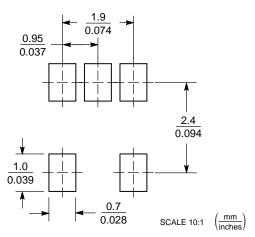
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: MILLIMETERS.

- CONTROLLING DIMENSION: MILLIMETERS.
 MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
 THICKNESS. MINIMUM LEAD THICKNESS IS THE
 MINIMUM THICKNESS OF BASE MATERIAL.
 DIMENSIONS A AND B DO NOT INCLUDE MOLD
 FLASH, PROTRUSIONS, OR GATE BURRS. MOLD
 FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT
 EXCEED 0.15 PER SIDE. DIMENSION A.
 ORICONAL CONSETPLICTION. AND ADDITIONAL
- OPTIONAL CONSTRUCTION: AN ADDITIONAL TRIMMED LEAD IS ALLOWED IN THIS LOCATION. TRIMMED LEAD NOT TO EXTEND MORE THAN 0.2 FROM BODY.

	MILLIN	IETERS				
DIM	MIN	MAX				
Α	3.00	BSC				
В	1.50	BSC				
C						
D	0.25	0.50				
G	0.95	BSC				
Н	0.01	0.10				
J	0.10	0.26				
K	0.20	0.60				
М	0 °	10°				
S	2.50	3.00				

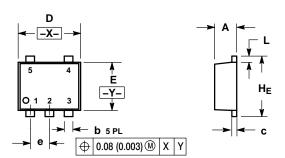
SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

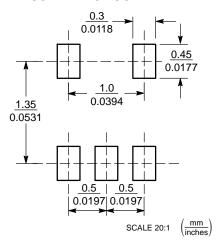
SOT-553, 5 LEAD CASE 463B ISSUE C



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETERS
 3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
 THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM
 THICKNESS OF BASE MATERIAL.

	М	ILLIMETE	RS	INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.50	0.55	0.60	0.020	0.022	0.024
b	0.17	0.22	0.27	0.007	0.009	0.011
С	0.08	0.13	0.18	0.003	0.005	0.007
D	1.55	1.60	1.65	0.061	0.063	0.065
E	1.15	1.20	1.25	0.045	0.047	0.049
е		0.50 BSC			0.020 BS0	
L	0.10	0.20	0.30	0.004	0.008	0.012
HE	1.55	1.60	1.65	0.061	0.063	0.065

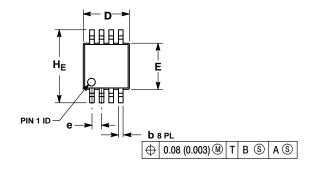
RECOMMENDED SOLDERING FOOTPRINT*

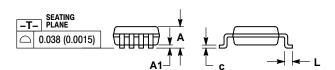


*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

Micro8™ CASE 846A-02 **ISSUE J**





NOTES:

- NOTES:

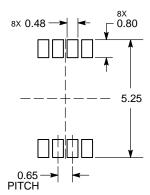
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

 3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS, MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED
- MOLD FLASH, PROTHOSIONS OR GATE BURRS SHALL NOT EACEED
 0.15 (0.006) PER SIDE.
 MOLD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
 846A-01 OBSOLETE, NEW STANDARD 846A-02.

	М	ILLIMETE	RS		INCHES	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α			1.10			0.043
A1	0.05	0.08	0.15	0.002	0.003	0.006
b	0.25	0.33	0.40	0.010	0.013	0.016
С	0.13	0.18	0.23	0.005	0.007	0.009
D	2.90	3.00	3.10	0.114	0.118	0.122
E	2.90	3.00	3.10	0.114	0.118	0.122
е		0.65 BSC			0.026 BSC)
L	0.40	0.55	0.70	0.016	0.021	0.028
HE	4.75	4.90	5.05	0.187	0.193	0.199

RECOMMENDED SOLDERING FOOTPRINT*

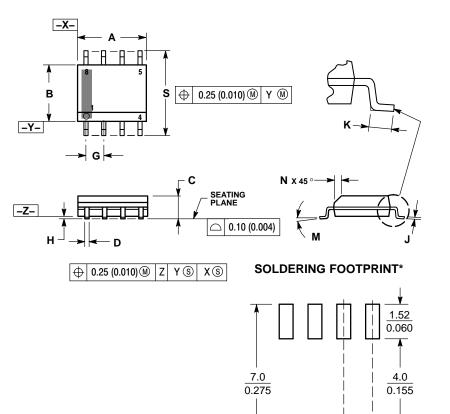


DIMENSION: MILLIMETERS

^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

SOIC-8 NB CASE 751-07 **ISSUE AK**



0.6

0.024

NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER. 3 DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.

- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- PER SIDE.

 DIMENSION D DOES NOT INCLUDE DAMBAR
 PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION SHALL BE 0.127 (0.005) TOTAL
 IN EXCESS OF THE D DIMENSION AT
 MAXIMUM MATERIAL CONDITION.
 751-01 THRU 751-06 ARE OBSOLETE. NEW
 CTANNA
- STANDARD IS 751-07.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
C	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
Н	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
М	0 °	8 °	0 °	8 °
Z	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

1.270

0.050

SCALE 6:1

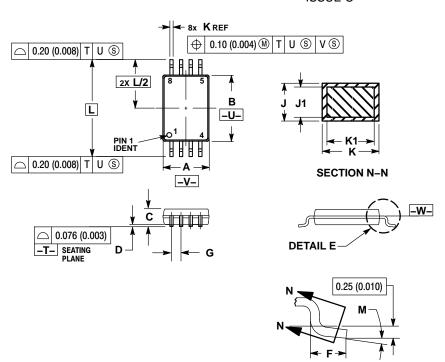
 $\left(\frac{\text{mm}}{\text{inches}}\right)$

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

TSSOP-8 **CASE 948S** ISSUE C

DETAIL E



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A DOES NOT INCLUDE MOLD FLASH.
 PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15
- (0.006) PER SIDE.

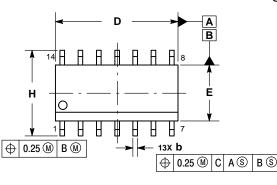
 4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010)
- PER SIDE.
 5. TERMINAL NUMBERS ARE SHOWN FOR
- REFERENCE ONLY.

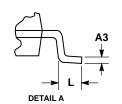
 6. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

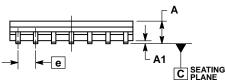
	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	2.90	3.10	0.114	0.122
В	4.30	4.50	0.169	0.177
C		1.10		0.043
ם	0.05	0.15	0.002	0.006
F	0.50	0.70	0.020	0.028
G	0.65 BSC		0.026 BSC	
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252 BSC	
М	0°	8°	0°	8°

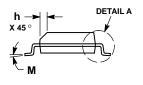
PACKAGE DIMENSIONS

SOIC-14 NB CASE 751A-03 ISSUE K







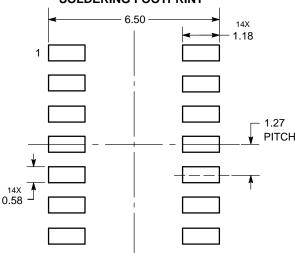


NOTES:

- DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS.
- 3. DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT MAXIMUM MATERIAL CONDITION.
- 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
- 5. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.

	MILLIN	IETERS	INCHES	
DIM	MIN	MAX	MIN	MAX
Α	1.35	1.75	0.054	0.068
A1	0.10	0.25	0.004	0.010
A3	0.19	0.25	0.008	0.010
b	0.35	0.49	0.014	0.019
D	8.55	8.75	0.337	0.344
Е	3.80	4.00	0.150	0.157
е	1.27 BSC		0.050 BSC	
Н	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.019
L	0.40	1.25	0.016	0.049
М	0 °	7°	0 °	7°

SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

Micro8 is a trademark of International Rectifier.

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor dates sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify a

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303–675–2175 or 800–344–3860 Toll Free USA/Canada Fax: 303–675–2176 or 800–344–3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

Phone: 81–3–5817–1050

^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

ON Semiconductor:

NCS2003SN2T1G NCV2003SN2T1G NCS2003XV53T2G NCS20034DR2G NCS20032DR2G NCS20032DR2G NCV20032DR2G NCV2002DR2G NCV2002DR2G NCV2002DR2G NCV2002DR2G NCV2002DR2G NCV2002DR2G NCV2002DR2G NCV2002D